

ELECTRONIC VALVE SPECIFICATIONS

SPECIFICATION MOA/CV.7054

Issue No. 1 Dated 18th December, 1959

AMENDMENT No.1

Page 1

Under PACKAGING please add:-

Mica washers and bushes to be packed with each device.

DIRD/RRE
MINISTRY OF AVIATION

February, 1961.

NS.47135/D

ELECTRONIC VALVE SPECIFICATION

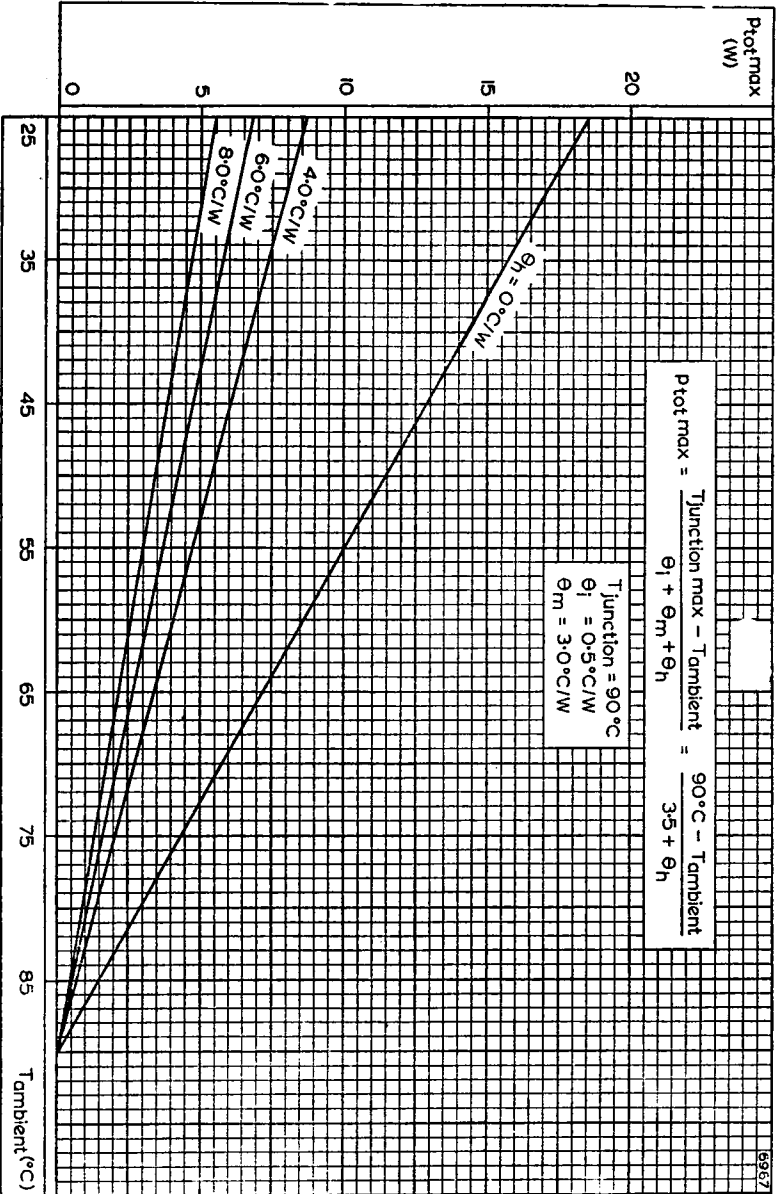
CV7054. ISSUE 1. DATED 18.12.59.

AMENDMENT NO.2

- Page 1. RATINGS
- (i) Collector current. Delete "or DC" and amend "(A) -1.0" to read "(A) -2.0"
 - (ii) Insert below new line reading "Max D.C. collector current (A) -1.0 Note B"
 - (iii) Emitter current. Delete "or DC" and amend "(A) 1.2" to read "(A) 2.2"
 - (iv) Insert below new line reading "Max. D.C. emitter current (A) 1.2 Note B".
 - (v) Max. junction temperature, Delete "75" and insert "90".
 - (vi) Base Current. Delete "pk. or".
- Page 2. CURVE Delete existing curve and insert attached curve.

R.R.E.

January, 1962.



ELECTRONIC VALVE SPECIFICATIONS
SPECIFICATION CV7054

ISSUE 1. DATED 18.12.64

Amendment No. 3

Page 1	Dimensions:	Delete:	Existing wording
		Insert:	K1007 Issue 3
			10.3.2.1.
			Type A and 10.4.2.1

Ministry of Aviation/R.R.E.

December, 1964.

(310252)

MINISTRY OF AVIATION - DLRD/RRE

VALVE ELECTRONIC
SEMICONDUCTOR DEVICE

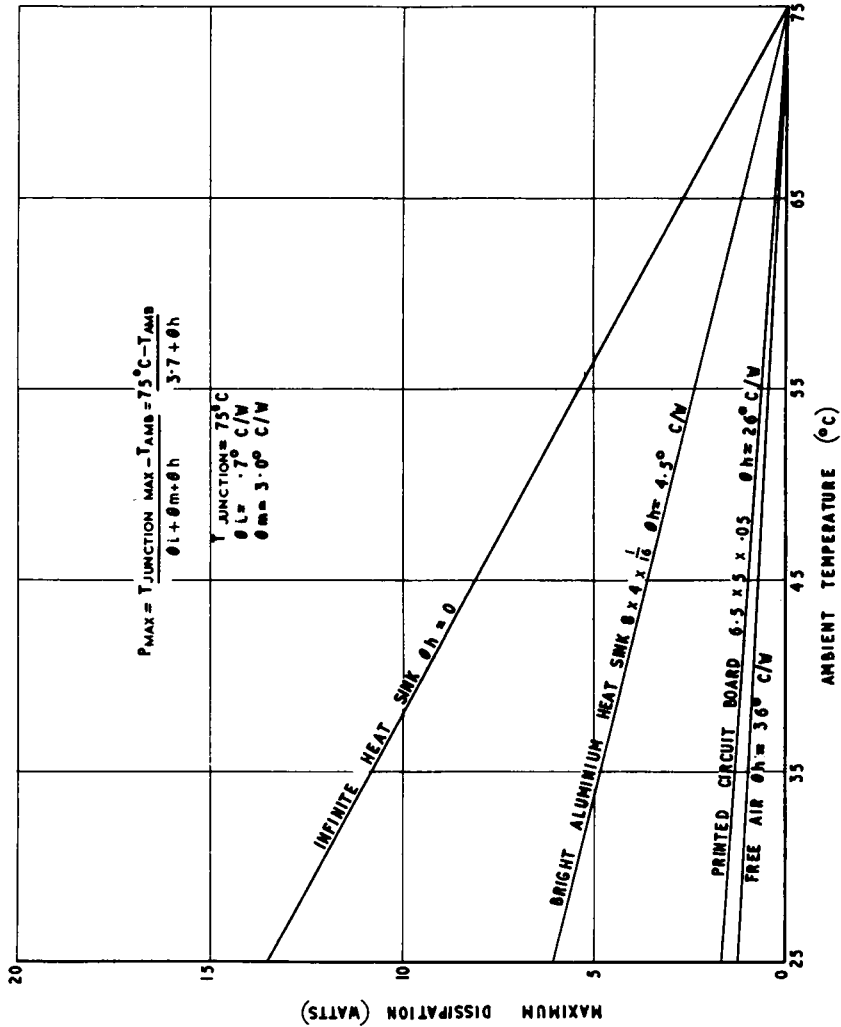
CV7054

Specification MOA/CV7054 Issue 1 dated 18.12.59 To be used in conjunction with K1007	<u>SECURITY</u>	
	Specification Unclassified	Valve Unclassified

indicates a change

TYPE OF DEVICE - Germanium High Current Switching Transistor CONSTRUCTION - Metal body PROTOTYPE - OC23		<u>MARKING</u> See K1007/4 CV number and if possible factory and date codes	
<u>RATING</u>		<u>DIMENSIONS</u>	
All limiting values are absolute		See K1007/A1	
	Note	(Outline) D4A	
		(Base) D4B	
		<u>MOUNTING POSITION</u>	
		Any Mica washers supplied must be used when insulation from chassis is necessary.	
		<u>PACKAGING</u>	
		K1007/14	
Max.pk.collector-emitter voltage $Z_{be} < 100 \text{ ohms or } +V_{be} > 0.5v$ (V)	-40		
Max.average or D.C. V_{ce} ($Z_{be} 100 \text{ ohms or } V_{be} > 0.5v$) (V)	-24	B	
Max.pk. V_{ce} ($Z_{be} > 10 \text{ Kohm}$) (V)	-16		
Max.average or D.C. V_{ce} ($Z_{b-e} > 10 \text{ Kohm}$) (V)	-10	B	
Max.pk. reverse base-emitter voltage (V)	15		
Max. average or D.C. V_{be} (V)	12	B	
Max.pk. or DC. collector current (A)	-1.0		
Max.pk. or D.C. emitter current (A)	1.2		
Max.pk. or DC. base current (A)	0.2		
Max.junction temperature ($^{\circ}C$)	75		
Max. thermal resistance junction to transistor mounting base Θ_m ($^{\circ}C/W$)	3.0	A	
Thermal resistance transistor mounting base to flat heat sink Θ_1 (a) with mica washer as supplied ($^{\circ}C/W$)	0.7	A	
(b) without mica washer ($^{\circ}C/W$)	0.3		
Max.dissipation (A)	75	A	
Max.Storage temperature ($^{\circ}C$)	-55		
Min. do. do. ($^{\circ}C$)	10		
Max. Continuous vibration (g)	500		
Max. Shock (g)	500		
<u>NOTES</u>			
A. $P_{max} = \frac{T_{jmax} - T_{amb}}{\Theta_m + \Theta_1 + \Theta_h}$ where Θ_h = the thermal resistance of the heat sink.			
B. Average over any 20 ms period			
C. JOINT SERVICE CATALOGUE NUMBER = 5960-99-037-2100			

MAXIMUM DISSIPATION PLOTTED AGAINST AMBIENT TEMPERATURE.



TESTS
 To be performed in addition to those applicable
 in K1007

K1007 ref.	TEST	TEST CONDITIONS	AQL %	Insp. Level	Sym- bol	Limits		UNITS
						Min.	Max.	
5.D.2	<u>GROUP A</u> Collector Base Leakage Current (1)	$V_{cb} = -24V$ $I_e = 0$		100%	I_{cbo}	-	250	μA
5.D.4.1	Large Signal Common emitter current gain (1)	$I_e = 300 \text{ mA}$ $V_{cb} = -2V$		100%	h_{FE}	75	300	
	Peak Collector Cut-off current	$V_{ce} = -40V \text{ pk}$ $V_{be} = + 0.5v$		100%	I_c	-	2	mApk
5.D.3.1	<u>GROUP B</u> Rise Time Fall Time Base emitter voltage (1)	Combined AQL Note 1 Note 2 $I_e = 300 \text{ mA}$ $V_{cb} = -2V$	2.5 0.65 0.65 0.65	II II II	t_r t_f V_{be}	- - 0.2	0.5 1.0 0.5	μS μS V
5.D.3.2	<u>GROUP C</u> Collector emitter Saturation voltage	Combined AQL $I_c = -1.0A$ $I_b = -30 \text{ mA}$	6.5 2.5	I	V_{ce}	0.15	0.85	V
5.D.2.2	Emitter base Leakage current	$V_{eb} = -12V$ $I_c = 0$	2.5	I		-	100	μA
5.D.4.1	Large signal common emitter current gain (2)	$I_e = 1.0A$ $V_{eb} = -2V$	2.5	I	h_{FE}	70	300	
5.D.3.1	Base emitter voltage (2)	$V_{cb} = -2V$ $I_e = 1.0A$	2.5	I	V_{be}	0.3	1.0	V
5.D.4.1	Large signal common emitter current gain (3)	$V_{cb} = -2V$ $I_e = 100 \text{ mA}$	2.5	I	h_{FE}	100	500	
5D.5.1	Base emitter voltage (3)	$V_{cb} = -2V$ $I_e = 100 \text{ mA}$	2.5	I	V_{be}	100	400	mV
5.D.2	<u>GROUP D</u> Collector Base Leakage current (2)	$V_{cb} = -24V$ $I_e = 0$ $T_A = 75^\circ C \pm 2^\circ C$	6.5	IC	I_{cbo}	-	10	mA
10.2	<u>GROUP E</u> Temperature cycling	No voltages Three cycles $-55^\circ C$ to $+ 75^\circ C$		IC				
10.3	Climatic cycling <u>Post Temperature and climatic cycling tests</u>	No voltages Combined AQL	10					

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TESTS (continued)

K1007 ref.	TEST	TEST CONDITIONS	AQL %	Insp. Level	Sym- bol	Limits		UNITS
						Min.	Max.	
8	<u>GROUP E (Cont'd)</u> Inoperatives	No voltages	6.5					
5.D.2	Collector Base leakage current	As in Group A	6.5		I_{cbo}	-	300	μA
5.D.4.1	Large signal common emitter current gain	As in Group A	6.5		h_{FE}	70	300	
	Pk collector cut off current	As in Group A	6.5		I_c	-	2.2	mAPk
11.3	Fatigue Shock	No voltages No Voltages Hammer Angle = 60°		IC TA				
	<u>Post Fatigue and Shock Tests</u>	Combined AQL	10					
8	Inoperatives	No voltages	6.5					
5.D.4.1	Common emitter large signal current gain	As in Group A	6.5		h_{FE}	75	300	
11.5	Soldering	No voltages	6.5	IC				
13	<u>GROUP F</u> Life	$P_c = 3.1$ watts $T_{amb} = 65^\circ C$ ± 2 C $V_{ce} = -12v$ min $T_j = 75^\circ C$		IC				
13.3	<u>Life Test end points 1000 hours</u>	Combined AQL	10					
8	Inoperatives	No voltages	6.5					
5.D.2	Collector Base leakage current	As in Group A	6.5		I_{cbo}	-	350	μA
5.D.4.1	Common emitter large signal current gain	As in Group A	6.5		h_{FE}	70	300	
	Pk Collector cut off current		6.5		I_c	-	3.0	mAPk

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TESTS (Cont'd)

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K1007 Ref.	TEST	TEST CONDITIONS	AQL %	Insp. Level	Sym- bol	Limits		UNITS
						Min.	Max	
13.7.1	Change in average $\frac{1}{h_{FE}}$ between 24 and 1000 hours	As in Group A	6.5		$\frac{\Delta}{h_{FE}}$.0015	
13.3	<u>Life Test and Points 240 hrs.</u> (Reduced dura- tion)							
8.	Inoperatives	No voltages						
5.D.2	Collector base leakage current	As in Group A			I _{cbo}		350	μ A
5.D.4.1	Common emitter large signal current	As in Group A			h_{FE}	70	300	
	Fk Collector cut-off current	As in Group A			I _c		3.0.	mAPk
	Change in average $\frac{1}{h_{FE}}$ between 24 and 240 hrs.	As in Group A			$\frac{\Delta}{h_{FE}}$ (AV.)		.0009	
13.4	Storage life(1)	No voltages t = 150 hours T = -55°C		I				
13.5	Storage life(2)	No voltages t = 150 hours T = + 75°C		I				
	<u>Post storage life test end points</u>							
	Repeat Group A tests	Combined AQL for Storage Life (1) Combined AQL for Storage Life (2)	2.5 4.0					
	<u>GROUP G</u> Re-test after 28 days holding period			100%				
8	Inoperatives	No voltages	0.5					
5.D.4.1	Common emitter large signal current gain	As in Group A	2.0		h_{FE}	75	300	

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NOTES

1. Rise time, measured in the circuit on page 7, is the time for the output current pulse to rise from 10% to 90% of its final value (i.e. to 315 mA)

At no time shall the overswing exceed a maximum of 368 mA.

2. This test shall be made in the circuit given on page 7.
Fall time is the time for the output current pulse to fall from 95% to 5% of its final value (i.e. 17.5 mA)

